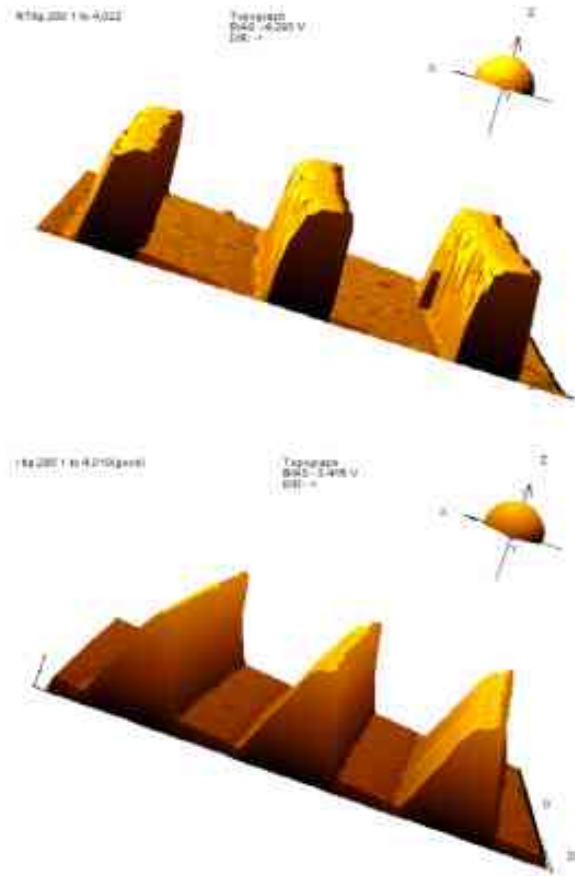


# Deep-Trench Images of 90nm Trench Structure using standard Si and C|D|I CNT AFM Probe



Actual AFM Data of 90nm trench structure showing comparison data between a standard silicon probe and a CNT AFM Probe.

The CCHAR high-aspect ratio CNT AFM probes, are designed for critical dimension measurements and imaging high-Z structures in materials science, metrology and life science applications. The standard CNT probe length is approximately 1 $\mu$ m overall with < 500nm of exposed CNT tip. These two dimensions can also be custom engineered to user specifications.

